



- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology



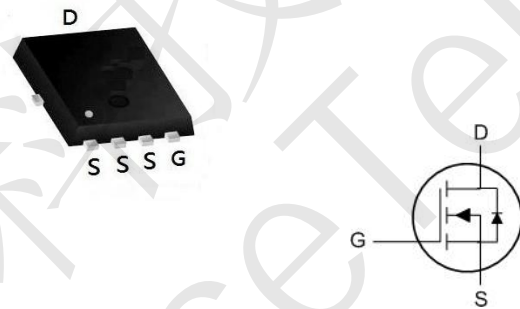
#### CST30100G Product Summary

BVDSS	RDSON	ID
30V	3.8mΩ	80A

#### CST30100G Description

The CST30100G is the high cell density Trench MOSFET, which provide excellent RDSON and gate charge for DC/DC converters application. The CST30100G meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

#### CST30100G PDFN5060-8L Pin Configuration



#### CST30100G Absolute Maximum Ratings (T<sub>c</sub>=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous	I <sub>D</sub>	80	A
Drain Current-Continuous(T <sub>c</sub> =100°C)	I <sub>D</sub> (100°C)	46	A
Pulsed Drain Current <sup>(Note 1)</sup>	I <sub>DM</sub>	200	A
Maximum Power Dissipation	P <sub>D</sub>	65	W
Derating factor		0.52	W/°C
Single pulse avalanche energy <sup>(Note 5)</sup>	E <sub>AS</sub>	150	mJ
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 To 150	°C

#### Thermal Characteristic

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	R <sub>θJC</sub>	1.92	°C/W
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#### CST30100G Electrical Characteristics (TC=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	30	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30V, V_{GS}=0V$	-	-	1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
<b>On Characteristics (Note 3)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1	1.6	2.5	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	3.8	5.0	m $\Omega$
		$V_{GS}=4.5V, I_D=20A$	-	6.9	11.0	
Forward Transconductance	$g_{FS}$	$V_{DS}=5V, I_D=20A$	20	-	-	S
<b>Dynamic Characteristics (Note 4)</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V,$ $F=1.0MHz$	-	1400	-	PF
Output Capacitance	$C_{oss}$		-	205	-	PF
Reverse Transfer Capacitance	$C_{rss}$		-	177	-	PF
<b>Switching Characteristics (Note 4)</b>						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=15V, I_D=20A$ $V_{GS}=10V, R_{GEN}=6\Omega$	-	9	-	nS
Turn-on Rise Time	$t_r$		-	8	-	nS
Turn-Off Delay Time	$t_{d(off)}$		-	28	-	nS
Turn-Off Fall Time	$t_f$		-	5	-	nS
Total Gate Charge	$Q_g$	$V_{DS}=15V, I_D=20A,$ $V_{GS}=10V$	-	32.3	-	nC
Gate-Source Charge	$Q_{gs}$		-	4.9	-	nC
Gate-Drain Charge	$Q_{gd}$		-	6.9	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage (Note 3)	$V_{SD}$	$V_{GS}=0V, I_S=20A$	-	0.85	1.2	V
Diode Forward Current (Note 2)	$I_S$		-	-	80	A
Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ C, I_F = 20A$ $di/dt = 100A/\mu s$ (Note 3)	-	-	27	nS
Reverse Recovery Charge	$Q_{rr}$		-	-	20	nC
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5. EAS condition:  $T_J=25^\circ C, V_{DD}=15V, V_G=10V, L=0.5mH, R_g=25\Omega$



CST30100G Typical Electrical and Thermal Characteristics (Curves)

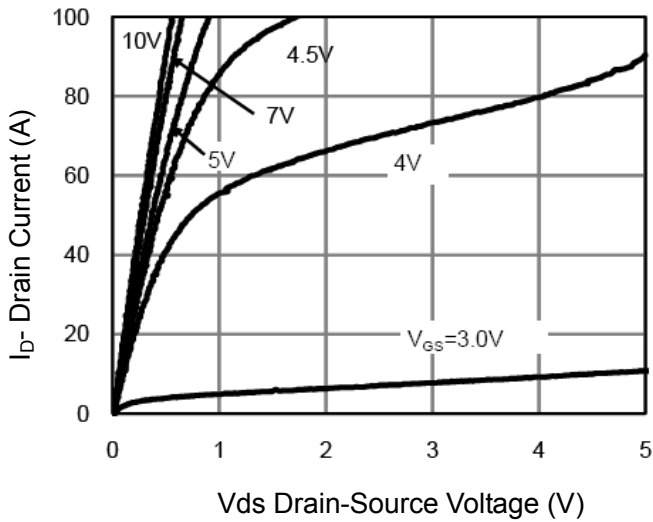


Figure 1 Output Characteristics

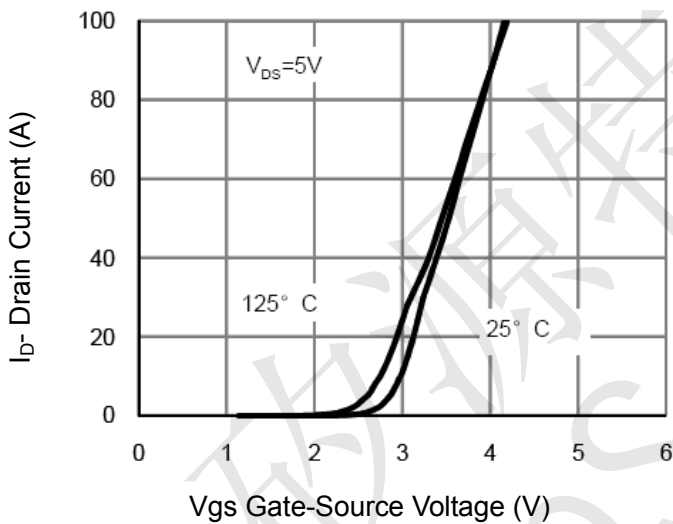


Figure 2 Transfer Characteristics

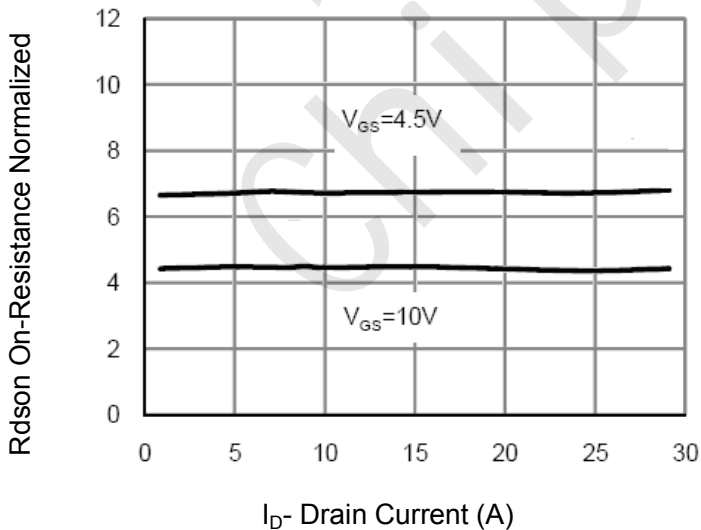


Figure 3  $R_{DS(on)}$  - Drain Current

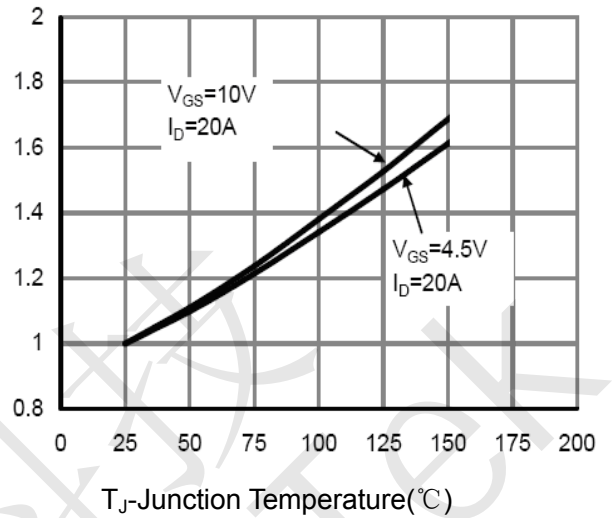


Figure 4  $R_{DS(on)}$  - Junction Temperature

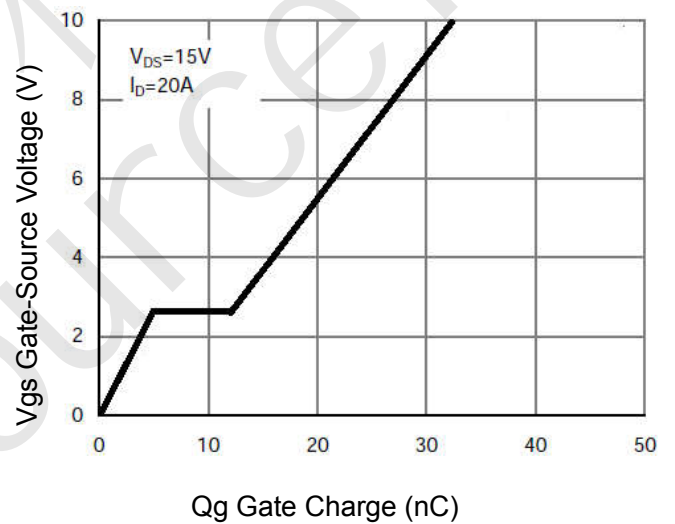


Figure 5 Gate Charge

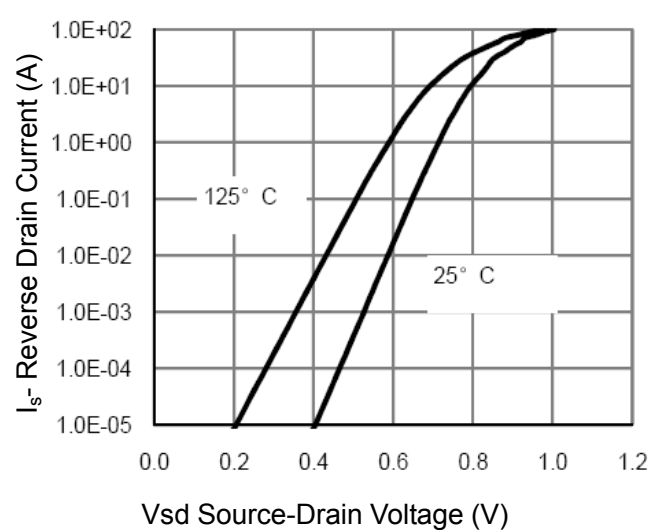
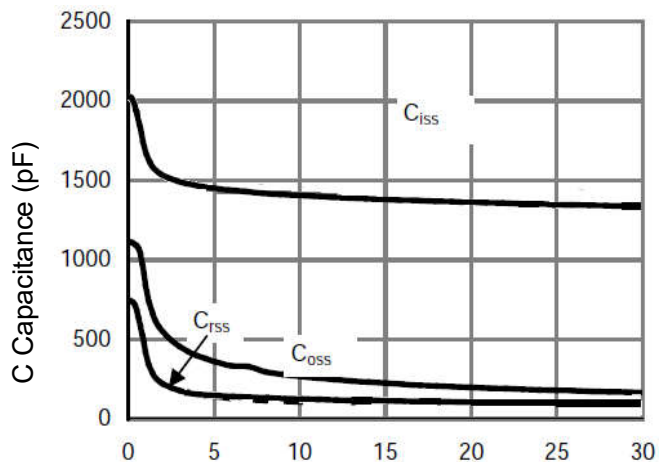


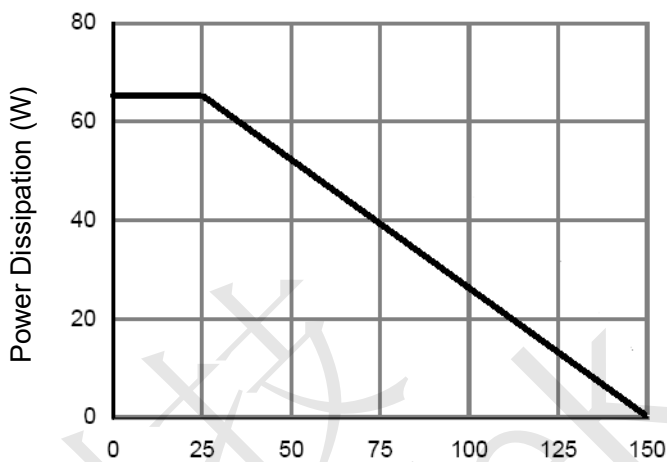
Figure 6 Source- Drain Diode Forward



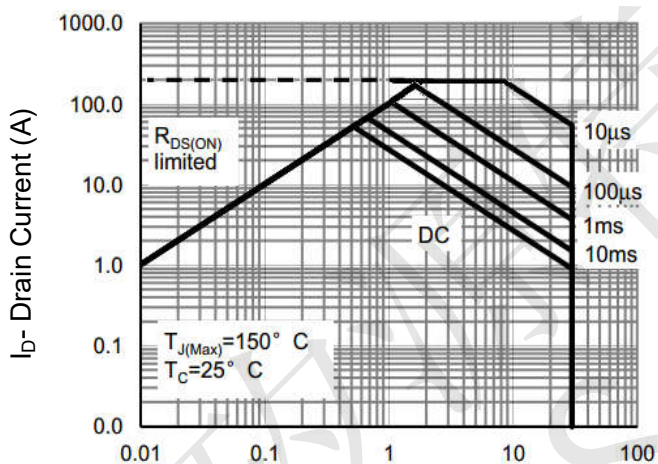
CST30100G N-Ch 30V Fast Switchin MOSFETs



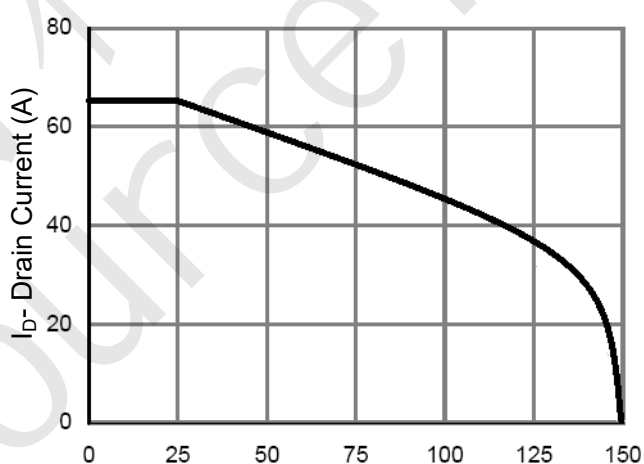
Vds Drain-Source Voltage (V)  
**Figure 7 Capacitance vs Vds**



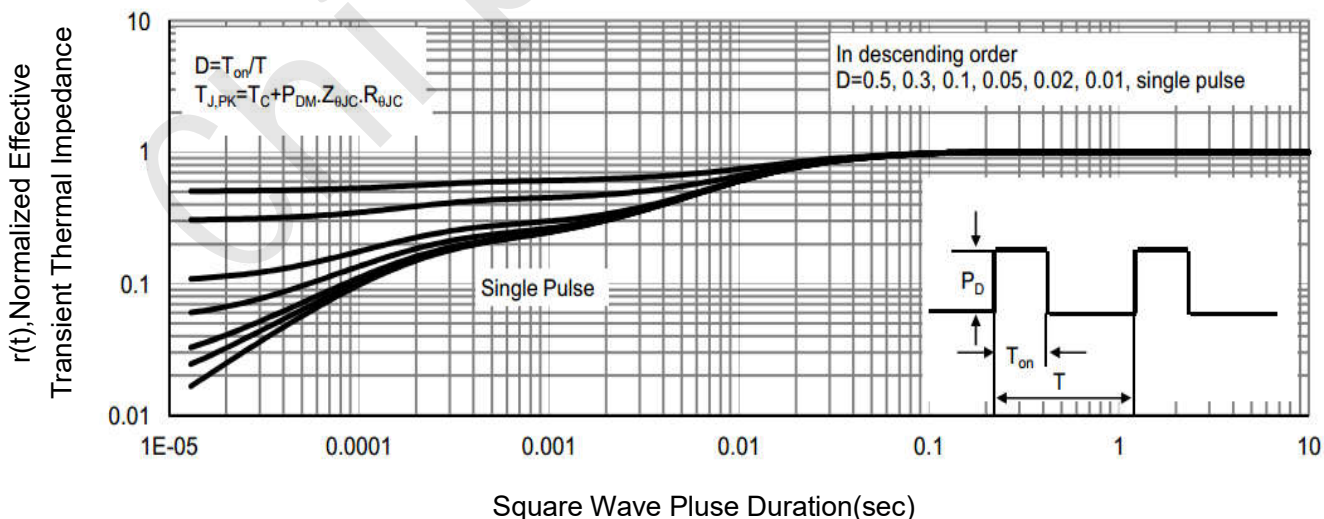
Tj-Junction Temperature(°C)  
**Figure 9 Power De-rating**



Vds Drain-Source Voltage (V)  
**Figure 8 Safe Operation Area**



Tj-Junction Temperature(°C)  
**Figure 10 ID Current- Junction Temperature**



**Figure 11 Normalized Maximum Transient Thermal Impedance**



CST30100G Test Circuit

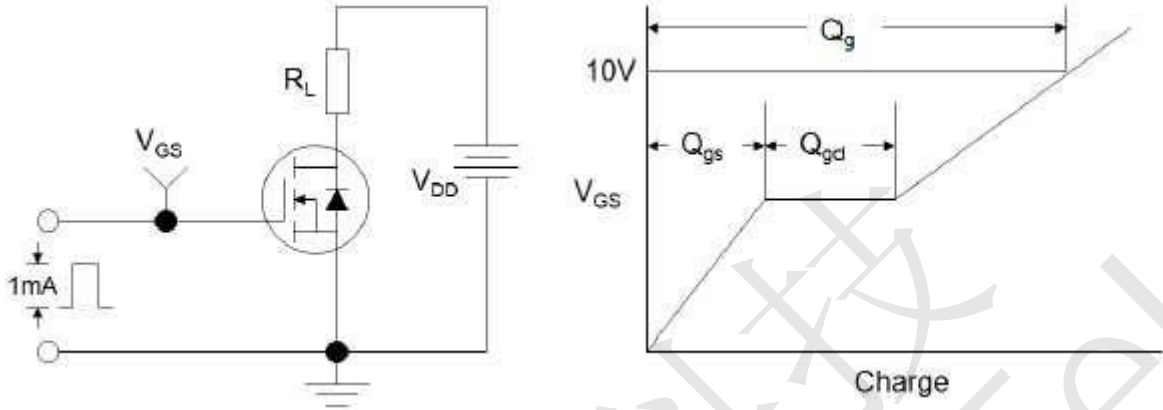


Figure1:Gate Charge Test Circuit & Waveform

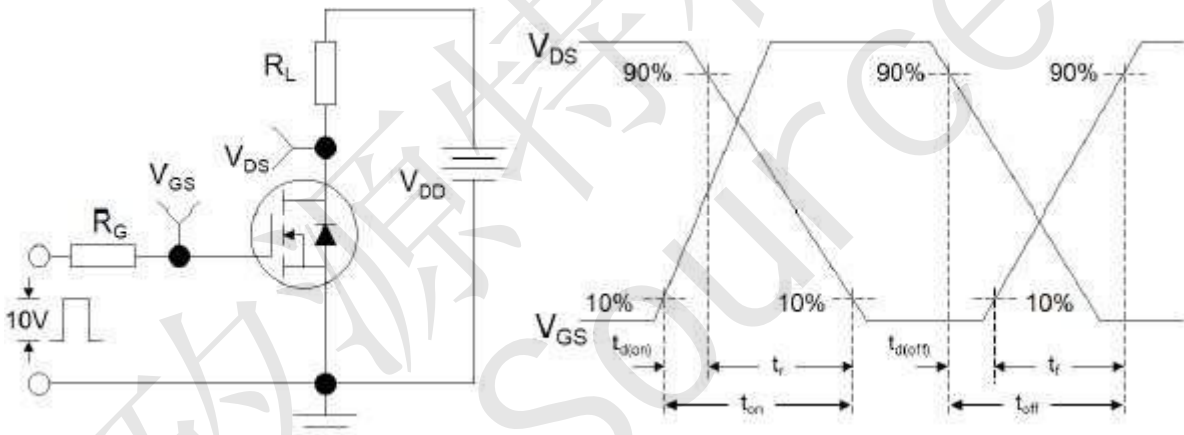


Figure 2: Resistive Switching Test Circuit & Waveforms

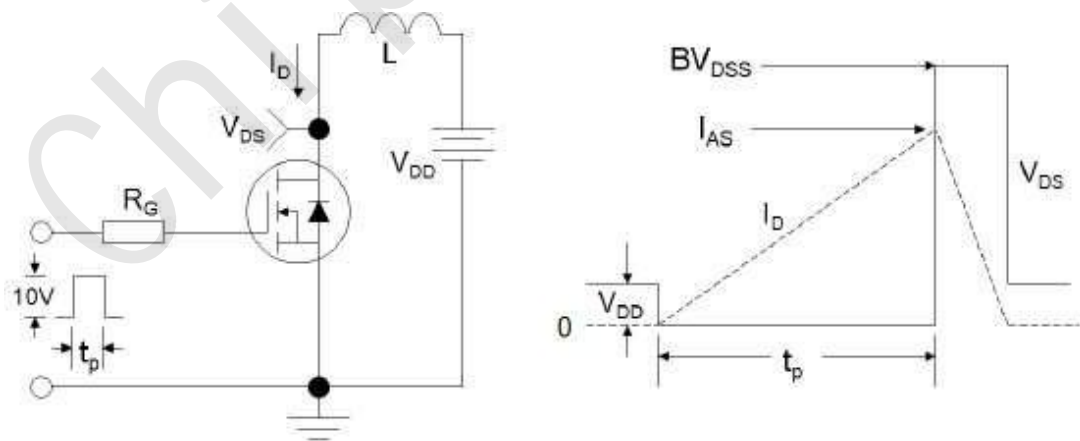
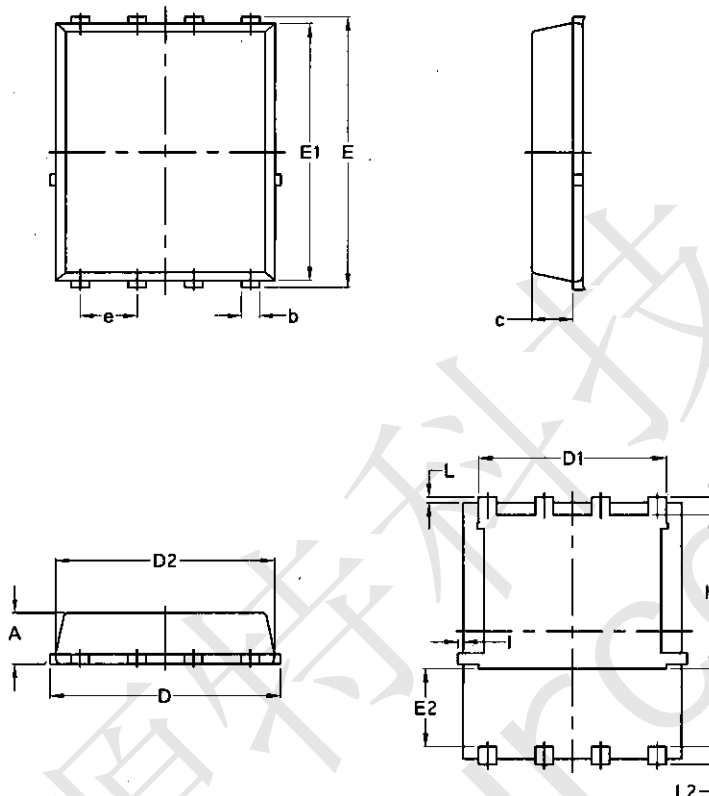


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



CST30100G Package Mechanical Data-PDFN5060-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070